# 74LVC595A

8-bit serial-in/serial-out or parallel-out shift register; 3-state

Rev. 2 — 20 June 2014

Product data sheet

## 1. General description

The 74LVC595A is an 8-bit serial-in/serial or parallel-out shift register with a storage register and 3-state outputs. Both the shift and storage register have separate clocks.

The input can be driven from either 3.3 V or 5 V devices. This feature allows the use of this device in a mixed 3.3 V and 5 V environment.

This device is fully specified for partial Power-down applications using  $I_{OFF}$ . The  $I_{OFF}$  circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

Data is shifted on the positive-going transitions of the SHCP input. The data in the shift register is transferred to the storage register on a positive-going transition of the STCP input. If both clocks are connected together, the shift register will always be one clock pulse ahead of the storage register.

The shift register has a serial input (DS) and a serial output (Q7S) for cascading purposes. It is also provided with asynchronous reset input MR (active LOW) for all 8 shift register stages. The storage register has 8 parallel 3-state bus driver outputs. Data in the storage register appears at the output whenever the output enable input (OE) is LOW.

## 2. Features and benefits

- 5 V tolerant inputs/outputs for interfacing with 5 V logic
- Wide supply voltage range from 1.2 V to 3.6 V
- CMOS low-power consumption
- Direct interface with TTL levels
- Balanced propagation delays
- All inputs have Schmitt-trigger action
- Complies with JEDEC standard JESD8-B/JESD36
- ESD protection:
  - ◆ HBM JESD22-A114-D exceeds 2000 V
  - ◆ CDM JESD22-C101-C exceeds 1000 V
- Specified from -40 °C to +85 °C and -40 °C to +125 °C.

# 3. Applications

- Serial-to-parallel data conversion
- Remote control holding register



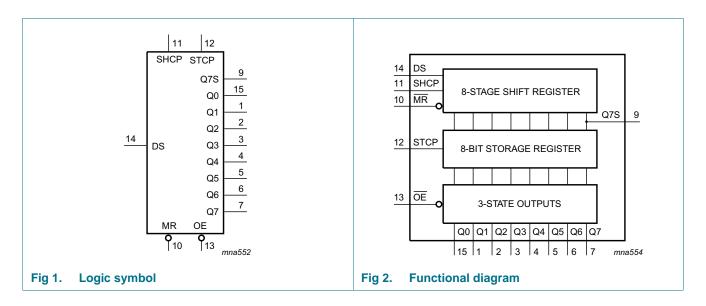
### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

# 4. Ordering information

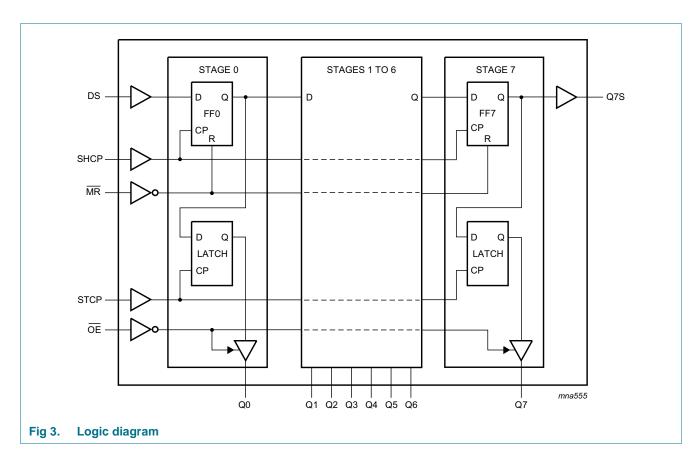
Table 1. Ordering information

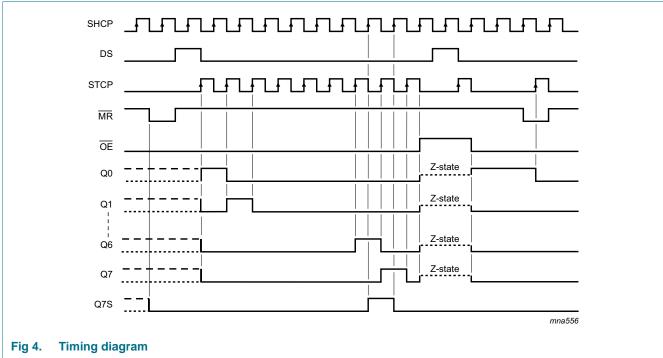
Type number	Package	Package							
	Temperature range	Name	Description	Version					
74LVC595AD	–40 °C to +125 °C	SO16	plastic small outline package; 16 leads; body width 3.9 mm	SOT109-1					
74LVC595APW	–40 °C to +125 °C	TSSOP16	plastic thin shrink small outline package; 16 leads; body width 4.4 mm	SOT403-1					
74LVC595ABQ	-40 °C to +125 °C	DHVQFN16	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 16 terminals; body $2.5 \times 3.5 \times 0.85$ mm	SOT763-1					

# 5. Functional diagram



8-bit serial-in/serial-out or parallel-out shift register; 3-state

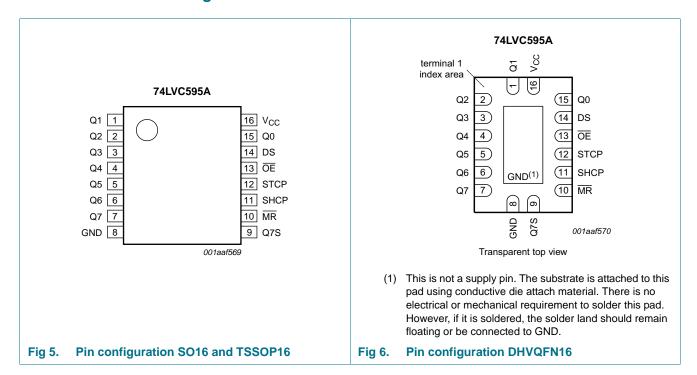




### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

## 6. Pinning information

#### 6.1 Pinning



## 6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
Q[0:7]	15, 1, 2, 3, 4, 5, 6, 7	parallel data output
GND	8	ground (0 V)
Q7S	9	serial data output
MR	10	master reset (active LOW)
SHCP	11	shift register clock input
STCP	12	storage register clock input
ŌĒ	13	output enable input (active LOW)
DS	14	serial data input
V <sub>CC</sub>	16	supply voltage

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# 7. Functional description

Table 3. Function table[1]

Input					Outpu	ıt	Function
SHCP	STCP	OE	MR	DS	Q7S	Qn	
Χ	Χ	L	L	Х	L	NC	a LOW-state on MR only affects the shift register
Χ	1	L	L	Х	L	L	empty shift register loaded into storage register
Χ	Χ	Н	L	Х	L	Z	shift register clear; parallel outputs in high impedance OFF-state
1	Х	L	Н	Н	Q6S	NC	logic HIGH-state shifted into shift register stage 0. Contents of all shift register stages shifted through, e.g. previous state of stage 6 (internal Q6S) appears on the serial output (Q7S).
X	<b>↑</b>	L	Н	Х	NC	QnS	contents of shift register stages (internal QnS) are transferred to the storage register and parallel output stages
<b>↑</b>	<b>↑</b>	L	Н	Х	Q6S	QnS	contents of shift register shifted through; previous contents of the shift register is transferred to the storage register and the parallel output stages

[1] H = HIGH voltage state;

L = LOW voltage state;

↑ = LOW-to-HIGH transition;

X = don't care:

NC = no change;

Z = high-impedance OFF-state.

# 8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>CC</sub>	supply voltage			-0.5	+6.5	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V		-50	-	mA
VI	input voltage		[1]	-0.5	+6.5	V
I <sub>OK</sub>	output clamping current	$V_O > V_{CC}$ or $V_O < 0$ V		-	±50	mA
Vo	output voltage	3-state	[1]	-0.5	6.5	V
		output HIGH or LOW state	[1]	-0.5	$V_{CC} + 0.5$	V
Io	output current	$V_O = 0 V \text{ to } V_{CC}$		-	±50	mA
I <sub>CC</sub>	supply current			-	100	mA
I <sub>GND</sub>	ground current			-100	-	mA
T <sub>stg</sub>	storage temperature			-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C}$	[2]	-	500	mW

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>[2]</sup> For SO16 packages: above 70 °C the value of  $P_{tot}$  derates linearly with 8 mW/K. For TSSOP16 packages: above 60 °C the value of  $P_{tot}$  derates linearly with 5.5 mW/K. For DHVQFN16 packages: above 60 °C the value of  $P_{tot}$  derates linearly with 4.5 mW/K.

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# 9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CC</sub>	supply voltage		1.65	-	3.6	V
		functional	1.2	-	-	V
V <sub>I</sub>	input voltage		0	-	5.5	V
Vo	output voltage	3-state	0	-	5.5	V
		output HIGH or LOW state	0	-	V <sub>CC</sub>	V
T <sub>amb</sub>	ambient temperature		-40	-	+125	°C
Δt/ΔV	input transition rise and fall rate	V <sub>CC</sub> = 1.65 V to 2.7 V	0	-	20	ns/V
		V <sub>CC</sub> = 2.7 V to 3.6 V	0	-	10	ns/V

## 10. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	–40 °C to	Unit	
			Min	Typ[1]	Max	Min	Max	
V <sub>IH</sub>	HIGH-level	V <sub>CC</sub> = 1.2 V	1.08	-	-	1.08	-	V
	input voltage	V <sub>CC</sub> = 1.65 V to 1.95 V	$0.65 \times V_{CC}$	-	-	$0.65 \times V_{CC}$	-	V
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.7	-	-	1.7	-	V
		V <sub>CC</sub> = 2.7 V to 3.6 V	2.0	-	-	2.0	-	V
V <sub>IL</sub>	LOW-level	V <sub>CC</sub> = 1.2 V	-	-	0.12	-	0.12	V
	input voltage	V <sub>CC</sub> = 1.65 V to 1.95 V	-	-	$0.35 \times V_{CC}$	-	$0.35 \times V_{CC}$	V
		V <sub>CC</sub> = 2.3 V to 2.7 V	-	-	0.7	-	0.7	V
		V <sub>CC</sub> = 2.7 V to 3.6 V	-	-	0.8	-	0.8	V
V <sub>OH</sub> HIGH-level output voltage	$V_I = V_{IH}$ or $V_{IL}$							
		$I_O = -100 \mu A;$ $V_{CC} = 1.65 \text{ V to } 3.6 \text{ V}$	V <sub>CC</sub> - 0.2	-	-	V <sub>CC</sub> – 0.3	-	V
		$I_{O} = -4 \text{ mA}; V_{CC} = 1.65 \text{ V}$	1.2	-	-	1.05	-	V
		$I_{O} = -8 \text{ mA}; V_{CC} = 2.3 \text{ V}$	1.8	-	-	1.65	-	V
		$I_{O} = -12 \text{ mA}; V_{CC} = 2.7 \text{ V}$	2.2	-	-	2.05	-	V
		$I_{O} = -18 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.4	-	-	2.25	-	V
		$I_{O} = -24 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.2	-	-	2.0	-	V
$V_{OL}$	LOW-level	$V_I = V_{IH}$ or $V_{IL}$						
	output voltage	$I_O = 100 \mu A;$ $V_{CC} = 1.65 \text{ V to } 3.6 \text{ V}$	-	-	0.2	-	0.3	V
		I <sub>O</sub> = 4 mA; V <sub>CC</sub> = 1.65 V	-	-	0.45	-	0.65	V
		$I_{O} = 8 \text{ mA}; V_{CC} = 2.3 \text{ V}$	-	-	0.6	-	0.8	V
		$I_{O}$ = 12 mA; $V_{CC}$ = 2.7 V	-	-	0.4	-	0.6	V
		$I_O = 24 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.55	-	0.8	V
lı	input leakage current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 5.5 V or GND	-	±0.1	±5	-	±20	μΑ

8-bit serial-in/serial-out or parallel-out shift register; 3-state

 Table 6.
 Static characteristics ...continued

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	–40 °C to	+125 °C	Unit
			Min	Typ[1]	Max	Min	Max	
l <sub>OZ</sub>	OFF-state output current	$V_{I} = V_{IH} \text{ or } V_{IL};$ [2] $V_{O} = 5.5 \text{ V or GND};$ $V_{CC} = 3.6 \text{ V}$	-	0.1	±10	-	±20	μА
I <sub>OFF</sub>	power-off leakage current	$V_{CC} = 0 \text{ V}; V_1 \text{ or } V_0 = 5.5 \text{ V}$	-	0.1	10	-	20	μА
I <sub>CC</sub>	supply current	$V_{CC} = 3.6 \text{ V};$ $V_I = V_{CC} \text{ or GND}; I_O = 0 \text{ A}$	-	0.1	10	-	40	μА
$\Delta I_{CC}$	additional supply current	per input pin; $V_{CC} = 1.65 \text{ V to } 3.6 \text{ V};$ $V_{I} = V_{CC} - 0.6 \text{ V};$ $I_{O} = 0 \text{ A}$	-	5	500	-	5000	μА
Cı	input capacitance	$V_{CC} = 0 \text{ V to } 3.6 \text{ V};$ $V_I = \text{GND to } V_{CC}$	-	5.0	-	-	-	pF

<sup>[1]</sup> All typical values are measured at  $V_{CC}$  = 3.3 V (unless stated otherwise) and  $T_{amb}$  = 25 °C.

## 11. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 13.

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	–40 °C to	Unit	
			Min	Typ[1]	Max	Min	Max	
t <sub>pd</sub>	propagation delay	SHCP to Q7S; see Figure 7	1					
		V <sub>CC</sub> = 1.2 V	-	17.5	-	-	-	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V	2.0	6.6	15.8	2.0	18.2	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.5	4.2	8.1	1.5	9.3	ns
		V <sub>CC</sub> = 2.7 V	1.5	4.7	7.6	1.5	8.7	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.5	4.0	6.7	1.5	7.7	ns
		STCP to Qn; see Figure 8	1					
		V <sub>CC</sub> = 1.2 V	-	16.8	-	-	-	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V	2.0	5.8	15.8	2.0	18.2	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.5	3.7	8.1	1.5	9.3	ns
		V <sub>CC</sub> = 2.7 V	1.5	4.0	7.6	1.5	8.7	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.2	3.3	6.7	1.2	7.7	ns
t <sub>PHL</sub>	HIGH to LOW	MR to Q7S; see Figure 11						
	propagation delay	V <sub>CC</sub> = 1.2 V	-	17.3	-	-	-	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V	2.0	6.9	15.8	2.0	18.2	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.5	4.3	8.1	1.5	9.3	ns
		V <sub>CC</sub> = 2.7 V		4.5	7.6	1.5	8.7	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.2	3.8	6.7	1.2	7.7	ns

<sup>[2]</sup> For transceivers, the parameter I<sub>OZ</sub> includes the input leaking current.

## 8-bit serial-in/serial-out or parallel-out shift register; 3-state

 Table 7.
 Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 13.

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	-40 °C to	Unit	
			Min	Typ[1]	Max	Min	Max	
en	enable time	OE to Qn; see Figure 12	[3]					
		V <sub>CC</sub> = 1.2 V	-	17.9	-	-	-	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V	2.0	6.4	14.1	2.0	16.2	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.5	4.2	8.0	1.5	9.2	ns
		V <sub>CC</sub> = 2.7 V	1.5	4.5	7.6	1.5	8.7	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.2	3.8	6.7	1.2	7.7	ns
dis	disable time	OE to Qn; see Figure 12	[4]					
		V <sub>CC</sub> = 1.2 V	-	9.6	-	-	-	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V	2.0	4.9	9.8	2.0	11.2	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.2	2.8	5.8	1.2	6.6	ns
		V <sub>CC</sub> = 2.7 V	1.5	3.7	6.2	1.5	7.1	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.2	3.5	5.7	1.2	6.5	ns
t <sub>W</sub> pulse width	SHCP, STCP HIGH or LOW; see Figure 7 and Figure 8							
	V <sub>CC</sub> = 1.65 V to 1.95 V	6.0	2.5	-	7.0	-	ns	
	V <sub>CC</sub> = 2.3 V to 2.7 V	5.0	2.0	-	5.5	-	ns	
		V <sub>CC</sub> = 2.7 V	4.5	1.5	-	5.0	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	4.0	1.5	-	4.5	-	ns
		MR LOW; see Figure 11						
		V <sub>CC</sub> = 1.65 V to 1.95 V	5.0	2.0	-	5.5	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	4.0	1.5	-	4.5	-	ns
		V <sub>CC</sub> = 2.7 V	2.5	1.0	-	3.0	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	2.5	1.0	-	3.0	-	ns
su	set-up time	DS to SHCP; see Figure 9						
		V <sub>CC</sub> = 1.65 V to 1.95 V	5.0	0.4	-	5.5	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	4.0	0.1	-	4.5	-	ns
		V <sub>CC</sub> = 2.7 V	2.0	0	-	2.5	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	2.0	-0.1	-	2.5	-	ns
		MR to STCP; see Figure 10						
		V <sub>CC</sub> = 1.65 V to 1.95 V	8.0	3.5	-	8.5	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	5.0	2.1	-	5.5	-	ns
		V <sub>CC</sub> = 2.7 V	4.0	1.8	-	4.5	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	4.0	1.7	-	4.5	-	ns
		SHCP to STCP; see Figure 8						
		V <sub>CC</sub> = 1.65 V to 1.95 V	8.0	3.5	-	8.5	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	5.0	2.1	-	5.5	-	ns
		V <sub>CC</sub> = 2.7 V	4.0	1.8	-	4.5	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	4.0	1.7	-	4.5	-	ns

### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

 Table 7.
 Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 13.

Symbol	Parameter	Conditions	-40	°C to +8	5 °C	-40 °C t	Unit	
			Min	Typ[1]	Max	Min	Max	
t <sub>h</sub>	hold time	DS to SHCP; see Figure 9						
		V <sub>CC</sub> = 1.65 V to 1.95 V	1.5	0.2	-	2.0	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	1.5	0.1	-	2.0	-	ns
		V <sub>CC</sub> = 2.7 V	1.5	-0.1	-	2.0	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	1.0	-0.2	-	1.5	-	ns
t <sub>rec</sub> recovery time	MR to SHCP; see Figure 11							
		V <sub>CC</sub> = 1.65 V to 1.95 V	5.0	-2.7	-	5.5	-	ns
		V <sub>CC</sub> = 2.3 V to 2.7 V	4.0	-1.5	-	4.5	-	ns
		V <sub>CC</sub> = 2.7 V	2.0	-1.0	-	2.5	-	ns
		V <sub>CC</sub> = 3.0 V to 3.6 V	2.0	-1.0	-	2.5	-	ns
f <sub>max</sub>	maximum frequency	SHCP or STCP; see Figure 7 and Figure 8						
		V <sub>CC</sub> = 1.65 V to 1.95 V	80	130	-	70	-	MHz
		V <sub>CC</sub> = 2.3 V to 2.7 V	100	140	-	90	-	MHz
		V <sub>CC</sub> = 2.7 V	110	150	-	100	-	MHz
		V <sub>CC</sub> = 3.0 V to 3.6 V	130	180	-	115	-	MHz
t <sub>sk(o)</sub>	output skew time	V <sub>CC</sub> = 3.0 V to 3.6 V	[5]	-	1.0	-	1.5	ns
C <sub>PD</sub>	power dissipation	$V_I = GND$ to $V_{CC}$	[6]					
	capacitance	V <sub>CC</sub> = 1.65 V to 1.95 V	-	50	-	-	-	pF
		V <sub>CC</sub> = 2.3 V to 2.7 V	-	45	-	-	-	pF
		V <sub>CC</sub> = 3.0 V to 3.6 V	-	44	-	-	-	pF

- [1] Typical values are measured at  $T_{amb}$  = 25 °C and  $V_{CC}$  = 1.8 V, 2.5 V, 2.7 V, and 3.3 V respectively.
- [2]  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ .
- [3]  $t_{en}$  is the same as  $t_{PZH}$  and  $t_{PZL}$ .
- [4]  $t_{dis}$  is the same as  $t_{PHZ}$  and  $t_{PLZ}$ .
- [5] Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.
- [6]  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \sum (C_L \times V_{CC}^2 \times f_o)$$
 where:

f<sub>i</sub> = input frequency in MHz;

f<sub>o</sub> = output frequency in MHz;

C<sub>L</sub> = output load capacitance in pF;

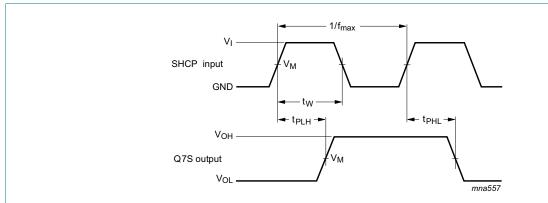
V<sub>CC</sub> = supply voltage in V;

N = number of inputs switching;

 $\sum (C_L \times V_{CC}{}^2 \times f_o)$  = sum of outputs.

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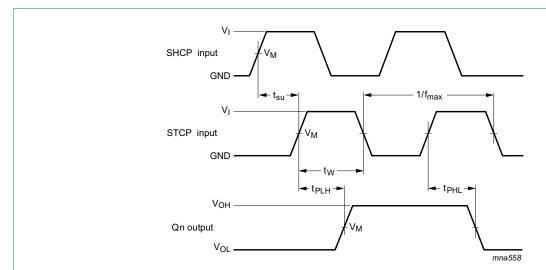
### 12. Waveforms



Measurement points are given in Table 8.

 $V_{OL}$  and  $V_{OH}$  are typical output voltage drops that occur with the output load.

Fig 7. The shift clock (SHCP) to serial data output (Q7S) propagation delays, the shift clock pulse width and maximum shift clock frequency

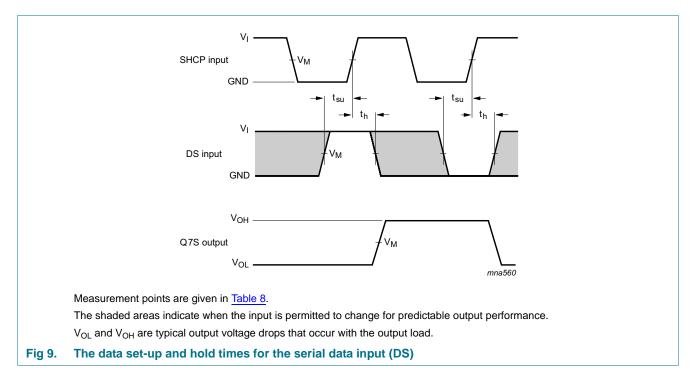


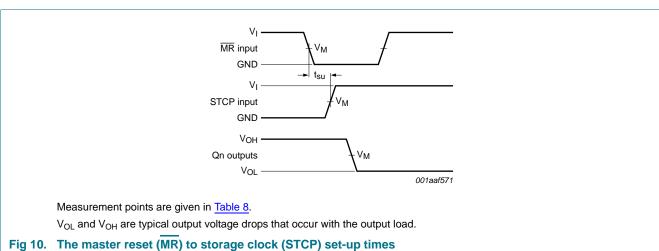
Measurement points are given in <u>Table 8</u>.

V<sub>OL</sub> and V<sub>OH</sub> are typical output voltage drops that occur with the output load.

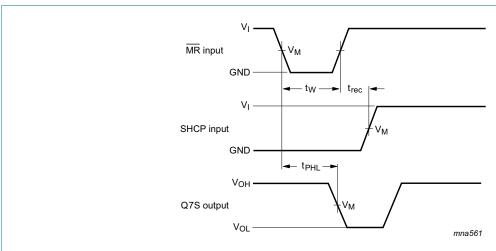
Fig 8. The storage clock (STCP) to parallel data output (Qn) propagation delays, the storage clock pulse width and the shift clock to storage clock set-up time

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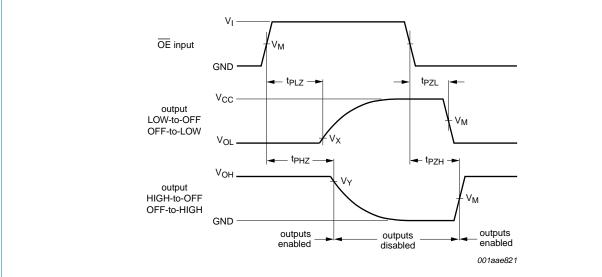
### 8-bit serial-in/serial-out or parallel-out shift register; 3-state



Measurement points are given in Table 8.

 $V_{\text{OL}}$  and  $V_{\text{OH}}$  are typical output voltage drops that occur with the output load.

Fig 11. The master reset (MR) pulse width, the master reset to serial data output (Q7S) propagation delays and the master reset to shift clock (SHCP) recovery time



Measurement points are given in Table 8.

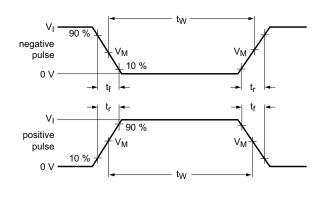
 $\ensuremath{V_{\text{OL}}}$  and  $\ensuremath{V_{\text{OH}}}$  are typical output voltage drops that occur with the output load.

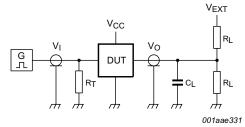
Fig 12. 3-state enable and disable times

Table 8. Measurement points

Supply voltage	Input	Output						
V <sub>CC</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>				
V <sub>CC</sub> < 2.7 V	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$	V <sub>OL</sub> + 0.15 V	V <sub>OH</sub> – 0.15 V				
$V_{CC} \ge 2.7 \text{ V}$	1.5 V	1.5 V	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V				

### 8-bit serial-in/serial-out or parallel-out shift register; 3-state





Test data is given in Table 9. Definitions for test circuit:

 $R_L$  = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to output impedance  $Z_o$  of the pulse generator.

 $V_{EXT}$  = External voltage for measuring switching times.

Fig 13. Test circuit for measuring switching times

Table 9. Test data

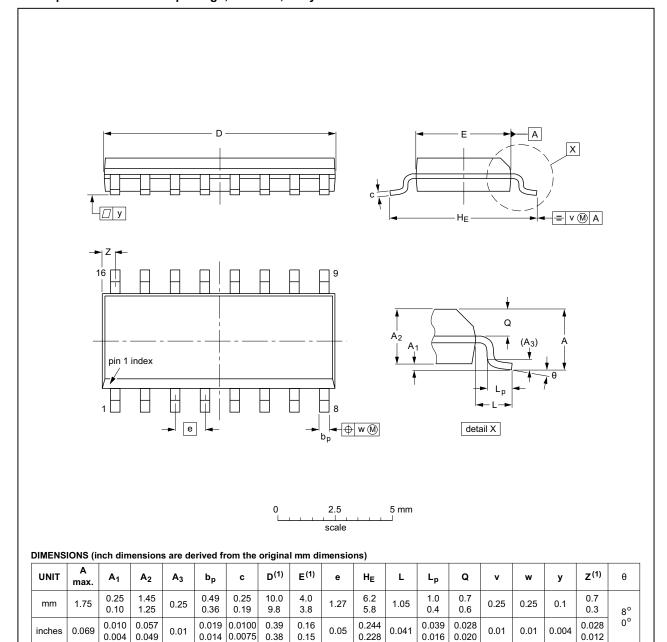
Supply voltage	Input	Input		Load		V <sub>EXT</sub>		
	VI	t <sub>r</sub> , t <sub>f</sub>	CL	R <sub>L</sub>	t <sub>PLH</sub> , t <sub>PHL</sub>	t <sub>PLZ</sub> , t <sub>PZL</sub>	t <sub>PHZ</sub> , t <sub>PZH</sub>	
1.2 V	V <sub>CC</sub>	≤ 2 ns	30 pF	1 kΩ	open	$2 \times V_{CC}$	GND	
1.65 V to 1.95 V	V <sub>CC</sub>	≤ 2 ns	30 pF	1 kΩ	open	$2 \times V_{CC}$	GND	
2.3 V to 2.7 V	V <sub>CC</sub>	≤ 2 ns	30 pF	500 Ω	open	$2 \times V_{CC}$	GND	
2.7 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	$2 \times V_{CC}$	GND	
3.0 V to 3.6 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	$2 \times V_{CC}$	GND	

### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

## 13. Package outline

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE VERSION		REFER	EUROPEAN	ISSUE DATE		
	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT109-1	076E07	MS-012				<del>99-12-27</del> 03-02-19

Fig 14. Package outline SOT109-1 (SO16)

74I VC595

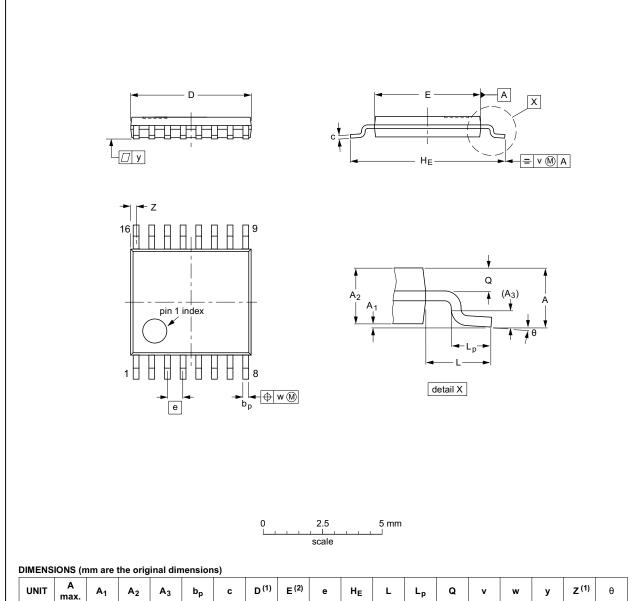
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### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

TSSOP16: plastic thin shrink small outline package; 16 leads; body width 4.4 mm

SOT403-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	<b>A</b> <sub>3</sub>	bp	С	D <sup>(1)</sup>	E (2)	е	HE	L	Lp	Q	٧	w	у	Z <sup>(1)</sup>	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.40 0.06	8° 0°

#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

				ISSUE DATE	
IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
	MO-153			<del>99-12-27</del> 03-02-18	
_					

Fig 15. Package outline SOT403-1 (TSSOP16)

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8-bit serial-in/serial-out or parallel-out shift register; 3-state

DHVQFN16: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 16 terminals; body 2.5 x 3.5 x 0.85 mm SOT763-1

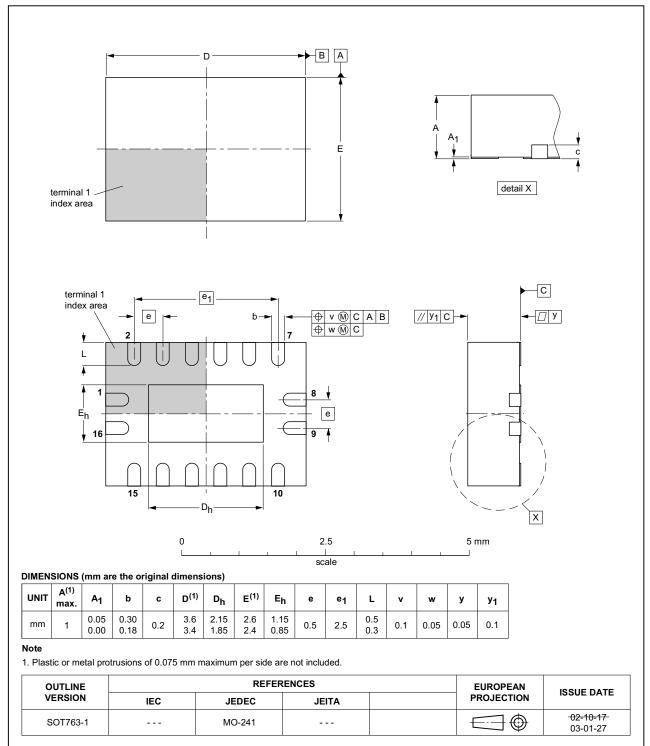


Fig 16. Package outline SOT763-1 (DHVQFN16)

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## 8-bit serial-in/serial-out or parallel-out shift register; 3-state

## 14. Abbreviations

#### Table 10. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
TTL	Transistor-Transistor Logic

# 15. Revision history

### Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
74LVC595A v.2	20140620	Product data sheet	-	74LVC595A v.1		
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>					
	Figure note for	r <u>Figure 6</u> added.				
74LVC595A v.1	20070529	Product data sheet	-	-		

#### 8-bit serial-in/serial-out or parallel-out shift register; 3-state

## 16. Legal information

#### 16.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
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